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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Sheet

1 of 7

Complete if Known

Application Number	09/942,392
Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown, JACK DINH
Attorney Docket Number	402801

Examiner Initials *	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
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U.S. PATENT DOCUMENTS

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Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ₆
		Office ³	Number ⁴	Kind Code ⁵ (if known)				
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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Sheet 4 of 7

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Application Number	09/942,392
Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DINH
Attorney Docket Number	402801

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Examiner Signature	<i>Janell</i>	Date Considered	09/06/04
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Sheet | 5 | of | 7

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Sheet 7 of 7

Complete if Known

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Filing Date	31 August 2001
First Named Inventor	Edward Raymond Dowski, Jr.
Group Art Unit	2873
Examiner Name	Unknown JACK DINH
Attorney Docket Number	402801

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
JD	48	Abstract of JP 60247611 A, published 12 July 1985 (Toshiba KK), Patent Abstracts of Japan, 6 May 1986, vol. 010, no. 119 (p-435), 1 page	
	49	POON, TING-CHUNG and MOTAMEDI, MASOUD, "Optical/digital incoherent image processing for extended depth of field", Applied Optics Vol. 26, no. 21, 1 November 1987, pp. 4612-4615	
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